

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/695,874	HAYAMI ET AL.	
	Examiner	Art Unit	
	Kin-Chan Chen	1765	

SEARCHED			
Class	Subclass	Date	Examiner
438	706	7/18/05	K-cc
	710		
	712		
	714		
	719		
	723		
	725		
438	745		
510	175		
510	176		
134	1.1		
	1.2		
134	1.3	7/18/05	K-cc
updated		9/2/05	K-cc

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	706 710	9/10/5	K-CC
	712		
	714		
	719		
	723		
438	725 745		
570	175		
510	176		
134	1.1 1.2		
134	9/11/5		K-CC